

## 1. Description

JRG40T120FUH is obtained by advanced Trench Field Stop (T-FS) technology which reduces the conduction loss, improves switching performance, and enhances the avalanche energy. The IGBT is suitable device for UPS, Welding, and high-speed switching.

### KEY CHARACTERISTICS

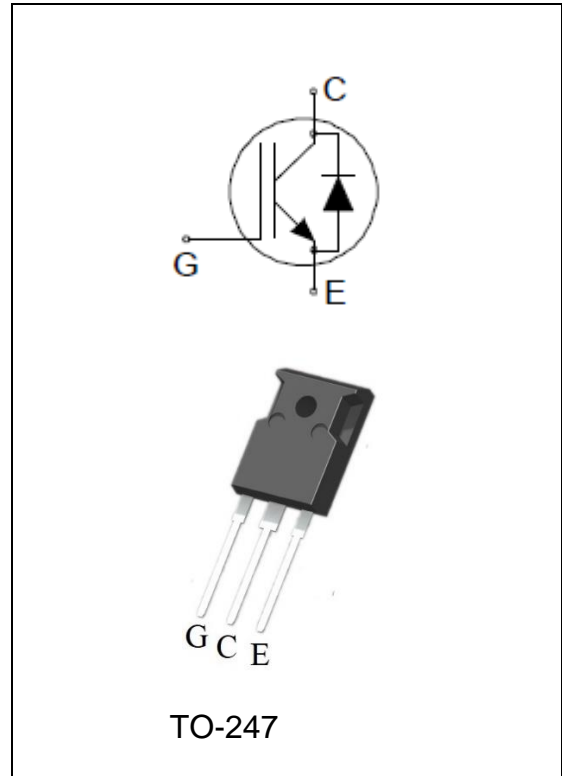
Parameter	Value	Unit
$V_{CES}$	1200	V
$I_C$	40	A
$V_{CE(sat).typ}$	2.0	V

### FEATURES

- Fast Switching
- LOW  $V_{CE(sat)}$
- Positive temperature coefficient
- Very soft, fast recovery anti-parallel diode
- RoHS product

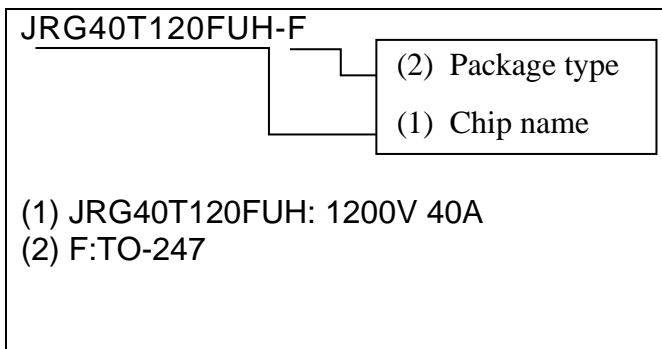
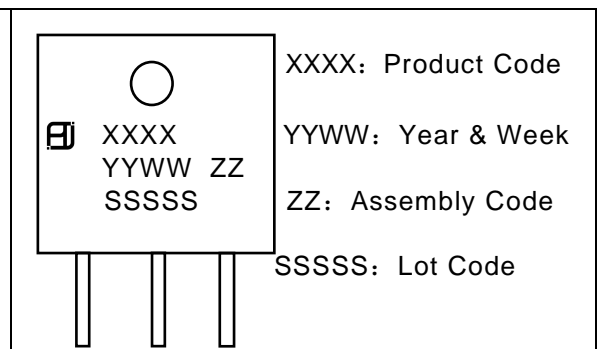
### APPLICATIONS

- UPS
- Welding Converters
- Converters with high switching frequency



## ORDERING INFORMATION

Ordering Codes	Package	Product Code	Packing
JRG40T120FUH-F	TO-247	G40T120FUH	Tube

<p>JRG40T120FUH-F</p>  <p>(1) JRG40T120FUH: 1200V 40A (2) F:TO-247</p>	 <p>XXXX: Product Code YYWW: Year &amp; Week ZZ: Assembly Code SSSSS: Lot Code</p>
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## 2. ABSOLUTE RATINGS

Symbol	Parameter	Values	Units
$V_{CES}$	Collector-Emitter Voltage	1200	V
$I_C$	Collector Current @ $T_C=25^{\circ}C$	80	A
	Collector Current @ $T_C=100^{\circ}C$	40	A
$I_{CM}$	Pulsed Collector Current, tp limited by $T_{Jmax}$	160	A
$I_F$	Diode Continuous Forward Current @ $T_C=25^{\circ}C$	40	A
	Diode Continuous Forward Current @ $T_C=100^{\circ}C$	20	A
$I_{FM}$	Diode Maximum Forward Current, limited by $T_{Jmax}$	80	A
$V_{GES}$	Gate-Emitter Voltage	$\pm 20$	V
$t_{SC}$	Short circuit withstand time $V_{GE}=15V, V_{CC}\leq 600V$ , Allowed number of short circuits < 1000, Times between short circuits: $\geq 1.0s, T_J \leq 150^{\circ}C$	10.0	$\mu s$
$P_D$	Power Dissipation @ $T_C=25^{\circ}C$	367	W
$T_{Jmax}, T_{stg}$	Operating Junction and Storage Temperature Range	150, $-55$ to $150$	$^{\circ}C$
$T_L$	Maximum Temperature for Soldering	260	$^{\circ}C$

## 3. Thermal characteristics

Symbol	Parameter	Values	Units
$R_{\theta JC}$	Junction-to-Case (IGBT)	0.34	$^{\circ}C/W$
$R_{\theta JC}$	Junction-to-Case (Diode)	0.8	$^{\circ}C/W$
$R_{\theta JA}$	Junction-to-Ambient	40	$^{\circ}C/W$

## 4. Electrical Characteristics

at  $T_C = 25^{\circ}C$ , unless otherwise specified

### Static Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$V_{CES}$	Collector-Emitter Breakdown Voltage	$V_{GE} = 0V, I_C = 250\mu A$	1200	--	--	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE} = 15V, I_C = 40A$	--	2.0	2.4	V
		$T_J=25^{\circ}C$	--	2.25		
		$T_J=100^{\circ}C$	--	2.35		



$V_{GE(TH)}$	Gate Threshold Voltage	$V_{CE} = V_{GE}, I_C = 1mA$	5.0	5.8	6.5	V
$V_F$	Diode Forward Voltage	$I_F=20A$ $T_J=25^\circ C$ $T_J=100^\circ C$ $T_J=150^\circ C$	--	1.95 1.65 1.50	2.55 -- --	V
$V_F$	Diode Forward Voltage	$I_F=40A$ $T_J=25^\circ C$ $T_J=100^\circ C$ $T_J=150^\circ C$	--	2.30 2.10 2.00	2.90 -- --	V
$I_{CES}$	Collector-Emitter Leakage Current	$V_{CE} = 1200V,$ $V_{GE} = 0V$	--	--	10	$\mu A$
$I_{GES(F)}$	Gate-Emitter Forward Leakage Current	$V_{GE} = +20V$	--	--	600	nA
$I_{GES(R)}$	Gate-Emitter Reverse Leakage Current	$V_{GE} = -20V$	--	--	-600	nA
Pulse width $t_p \leq 300\mu s, \delta \leq 2\%$						

### Dynamic Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$C_{iss}$	Input Capacitance	$V_{GE}=0V$ $V_{CE}=25V$ $f=1.0MHz$	--	3690	--	pF
$C_{oss}$	Output Capacitance		--	322	--	
$C_{rss}$	Reverse Transfer Capacitance		--	202	--	
$Q_G$	Gate charge	$V_{CC}=960V$ $I_{CE}=40A$ $V_{GE}=15V$	--	274	--	nC
$Q_{GE}$	Gate-emitter charge		--	21	--	
$Q_{GC}$	Gate-collector charge		--	188	--	
$I_{C(SC)}$	Short circuit collector current Max.1000 short circuits, Times between short circuits: $\geq 1.0s$	$V_{GE}=15.0V, V_{CC} \leq 600V,$ $t_{sc} \leq 10\mu s, T_J \leq 150^\circ C$		160		A

### IGBT Switching Characteristics, at $T_J=25^\circ C$

Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$t_{d(on)}$	Turn-on Delay Time	$I_C = 40A$ $V_{CC} = 600V$ $V_{GE} = 15V$ $R_G = 10\Omega$ $T_J = 25^\circ C$ Inductive Load	--	45	--	ns
$t_r$	Rise Time		--	93	--	
$t_{d(off)}$	Turn-Off Delay Time		--	286	--	
$t_f$	Fall Time		--	76	--	
$E_{on}$	Turn-On Switching Loss			--	5.0	--

$E_{off}$	Turn-Off Switching Loss		--	1.5	--	
$E_{ts}$	Total Switching Loss		--	6.5	--	

**IGBT Switching Characteristics, at  $T_J=150^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$t_{d(on)}$	Turn-on Delay Time	$I_C = 40\text{A}$ $V_{CC} = 600\text{V}$ $V_{GE} = 15\text{V}$ $R_G = 10\Omega$ $T_J = 150^\circ\text{C}$ Inductive Load	--	43	--	ns
$t_r$	Rise Time		--	85	--	
$t_{d(off)}$	Turn-Off Delay Time		--	342	--	
$t_f$	Fall Time		--	194	--	
$E_{on}$	Turn-On Switching Loss		--	5.2	--	mJ
$E_{off}$	Turn-Off Switching Loss		--	2.7	--	
$E_{ts}$	Total Switching Loss		--	7.9	--	

**Diode Characteristics, at  $T_J=25^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$T_{rr}$	Reverse Recovery Time	$I_F = 20\text{A}$ , $di/dt = 200\text{A}/\mu\text{s}$ , $T_J = 25^\circ\text{C}$	--	50	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	350	--	nC
$I_{rrm}$	Reverse Recovery Current		--	12	--	A
$T_{rr}$	Reverse Recovery Time	$I_F = 40\text{A}$ , $di/dt = 200\text{A}/\mu\text{s}$ , $T_J = 25^\circ\text{C}$	--	56	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	380	--	nC
$I_{rrm}$	Reverse Recovery Current		--	16	--	A

**Diode Characteristics, at  $T_J=150^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$T_{rr}$	Reverse Recovery Time	$I_F = 20\text{A}$ , $di/dt = 200\text{A}/\mu\text{s}$ , $T_J = 150^\circ\text{C}$	--	64	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	840	--	nC
$I_{rrm}$	Reverse Recovery Current		--	16	--	A
$T_{rr}$	Reverse Recovery Time	$I_F = 40\text{A}$ , $di/dt = 200\text{A}/\mu\text{s}$ , $T_J = 150^\circ\text{C}$	--	74	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	880	--	nC
$I_{rrm}$	Reverse Recovery Current		--	20	--	A



## 5. Characteristics Curves

Figure 1. Forward Bias Safe Operating Area

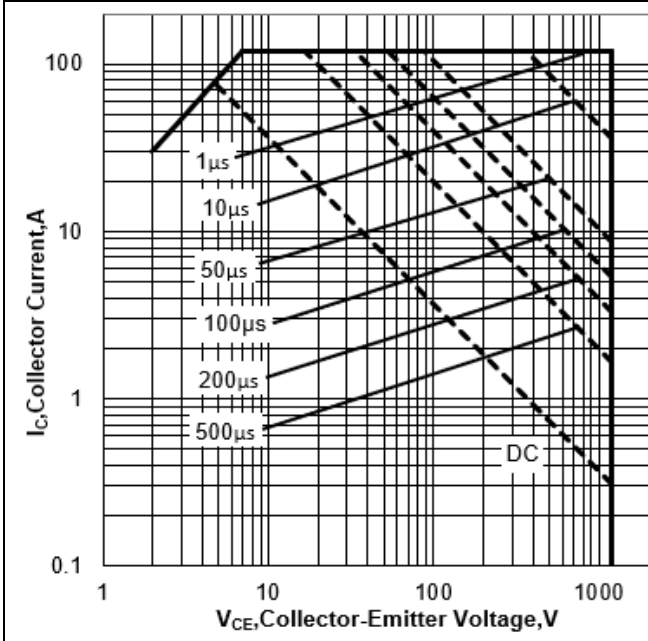


Figure 2. Power Dissipation vs Case Temperature

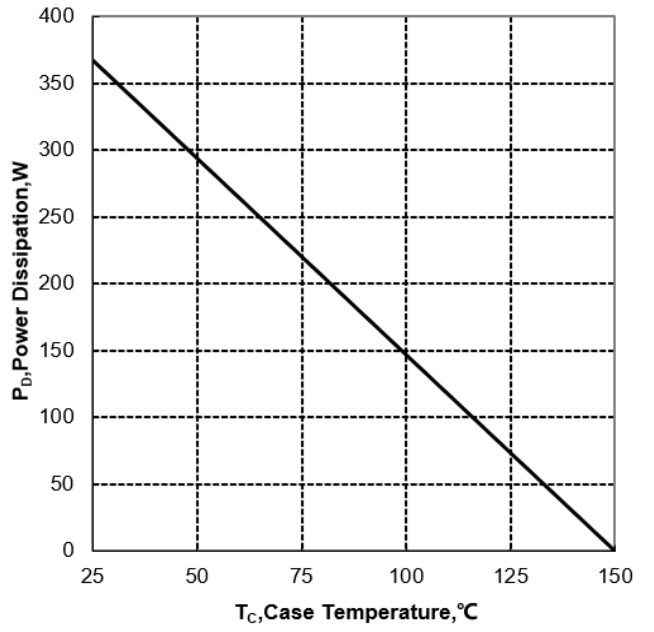


Figure 3. Collector Current vs Case Temperature

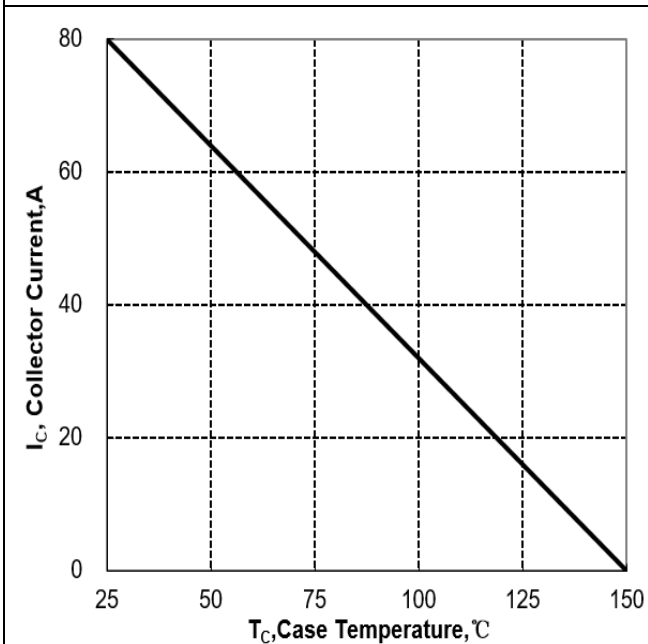


Figure 4. Typical Transfer Characteristics

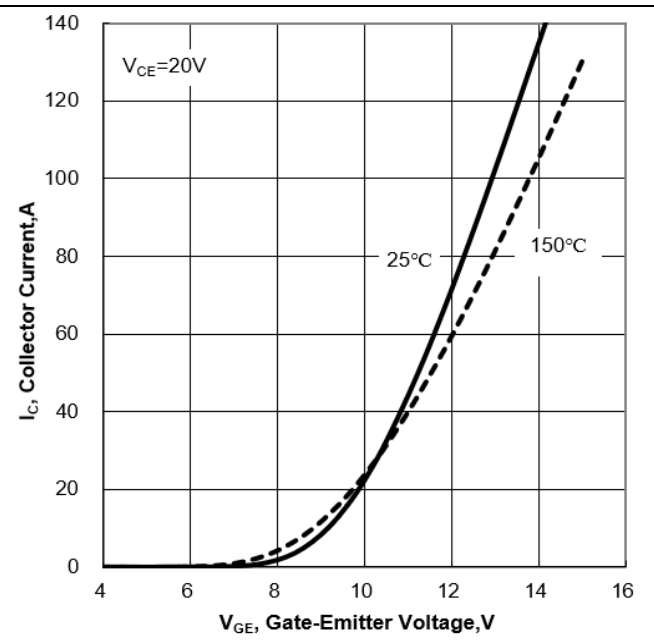




Figure 5. Typical Output Characteristics  
( $T_J=25^\circ\text{C}$ )

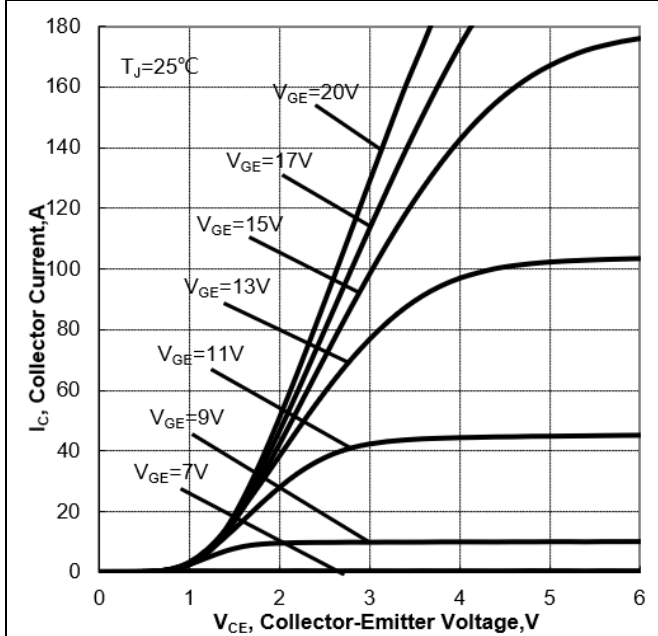


Figure 6. Typical Output Characteristics  
( $T_J=150^\circ\text{C}$ )

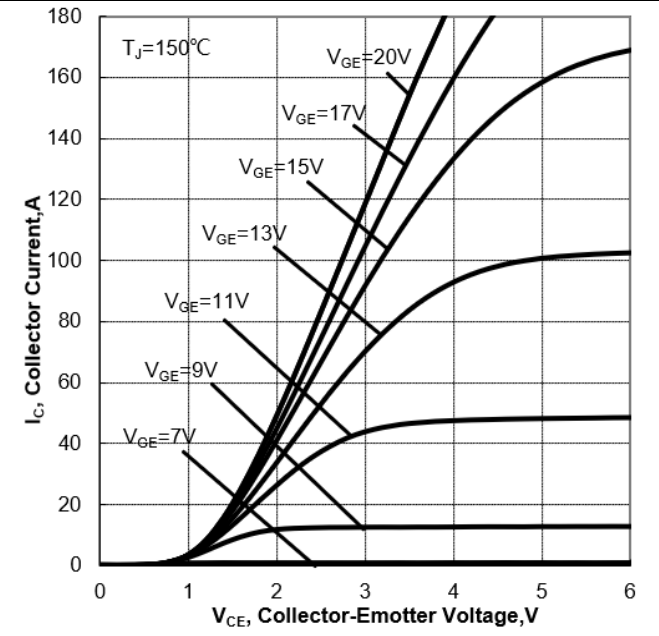


Figure 7. Typical Collector-Emmitter Saturation Voltage vs Junction Temperature

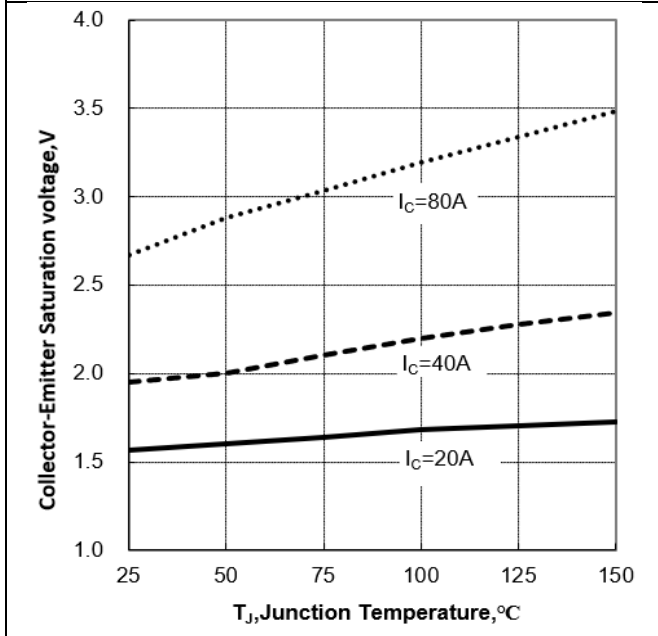
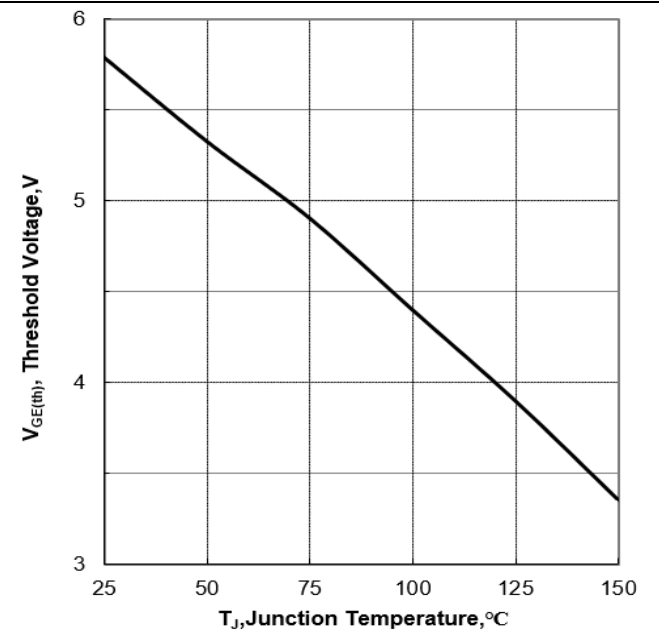


Figure 8. Typical Gate-Emmitter Threshold Voltage vs Junction Temperature



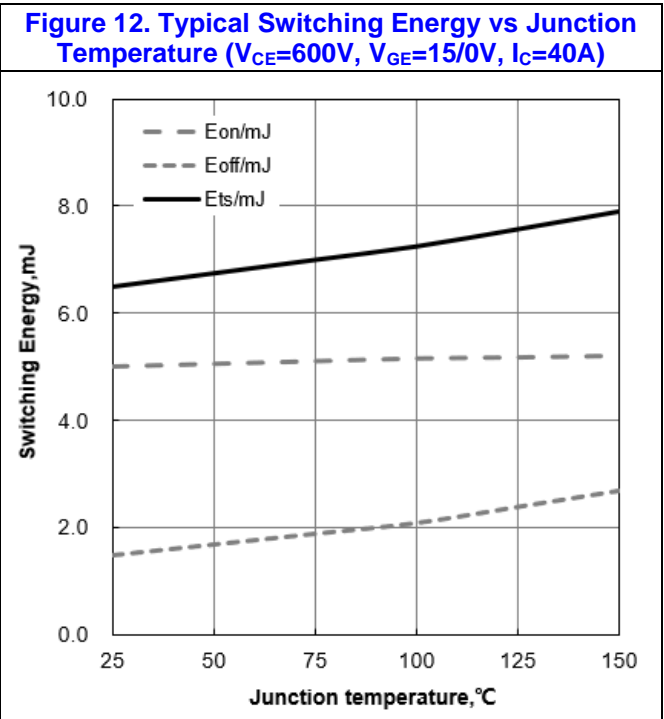
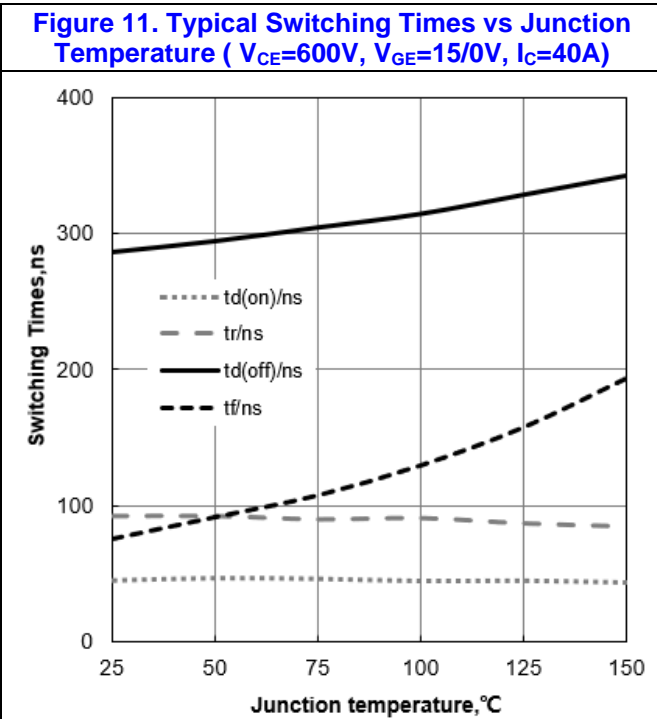
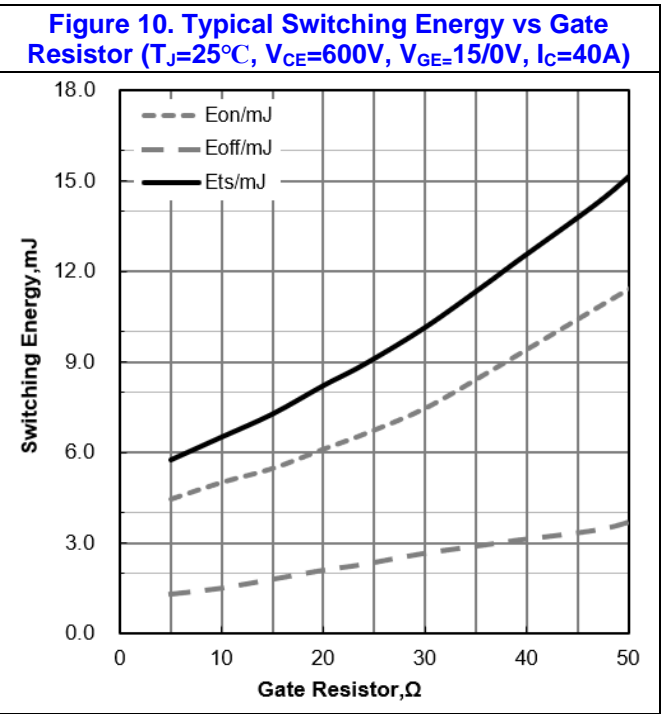
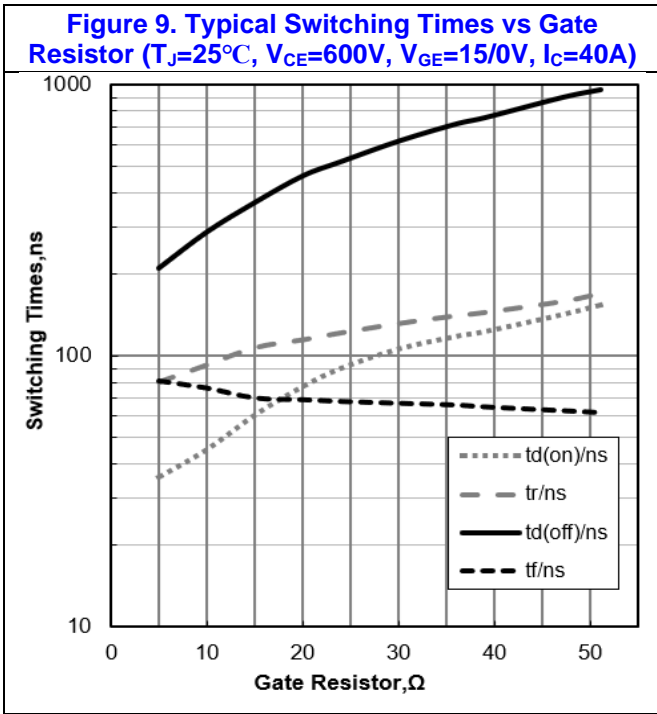




Figure 13. Typical Switching Times vs Collector Current ( $T_J=25^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=15/0\text{V}$ )

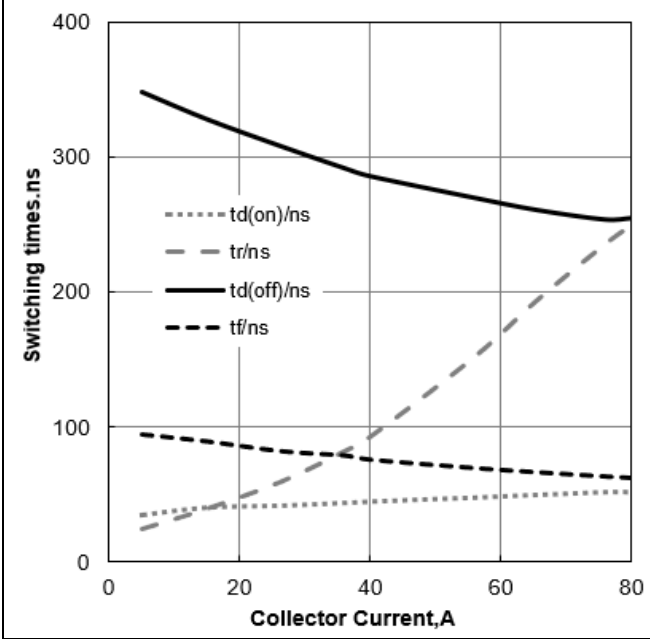


Figure 14. Typical Switching Energy vs Collector Current ( $T_J=25^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=15/0\text{V}$ )

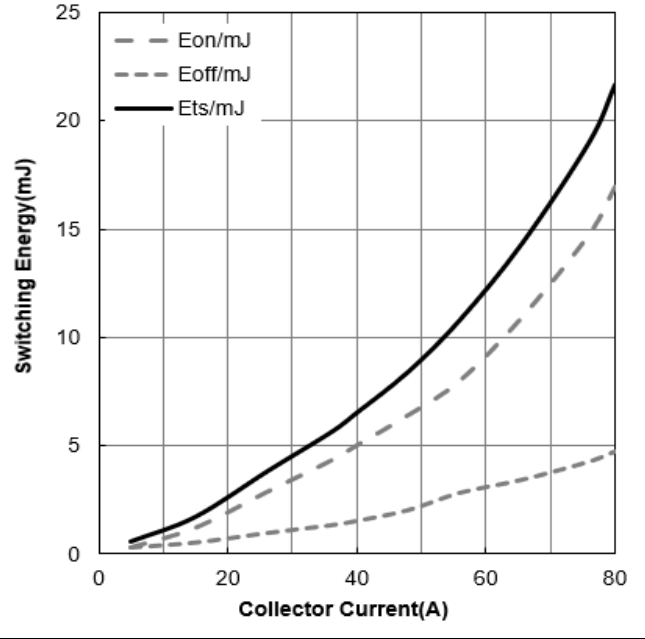


Figure 15. Typical Switching Times vs  $V_{CE}$  ( $T_J=25^\circ\text{C}$ ,  $V_{GE}=15/0\text{V}$ ,  $I_C=40\text{A}$ )

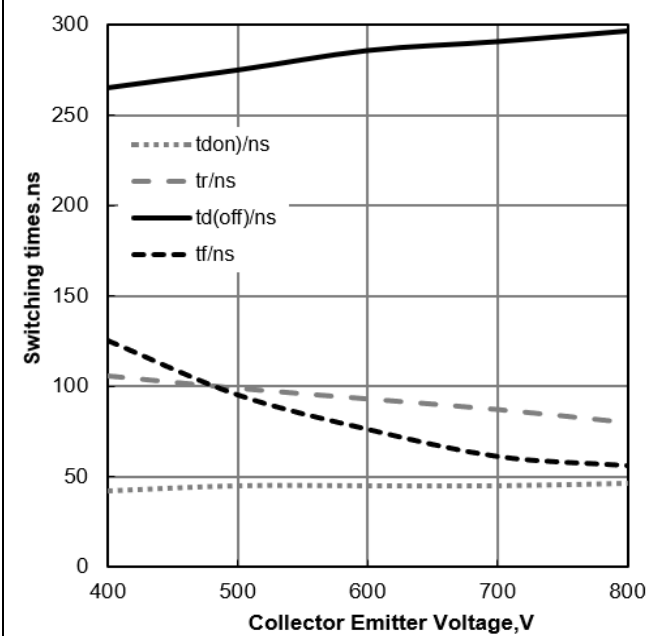


Figure 16. Typical Switching Energy vs  $V_{CE}$  ( $T_J=25^\circ\text{C}$ ,  $V_{GE}=15/0\text{V}$ ,  $I_C=40\text{A}$ )

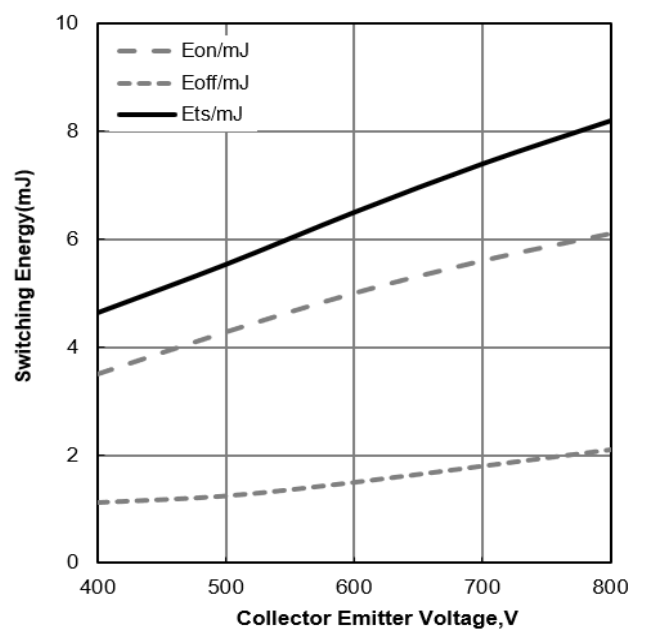






Figure 17. Typical Gate Charge

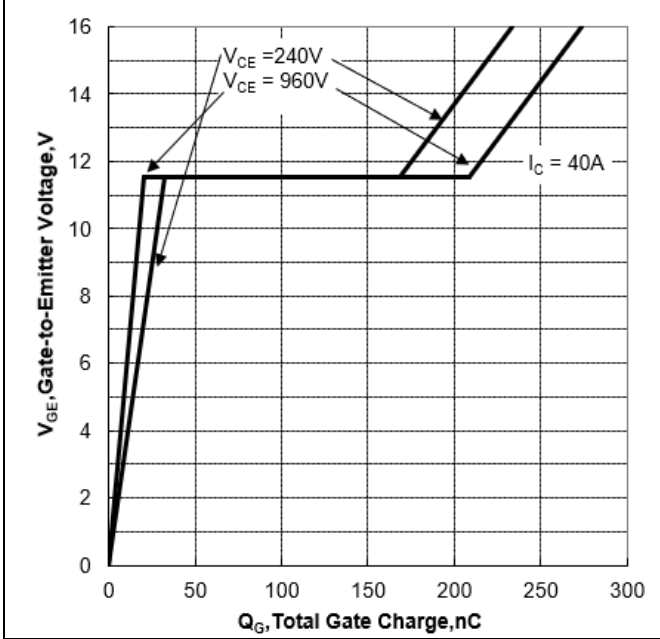


Figure 18. Typical Capacitance vs Collector-Emitter Voltage

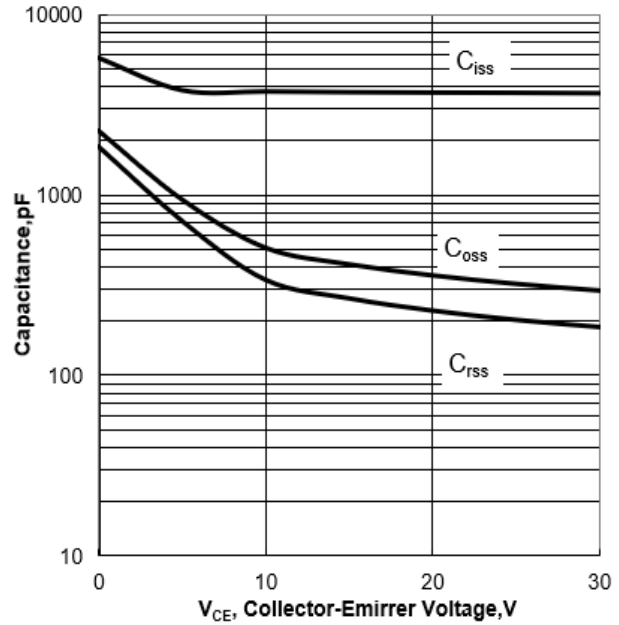


Figure 19. IGBT Transient Thermal Impedance vs Pulse Width

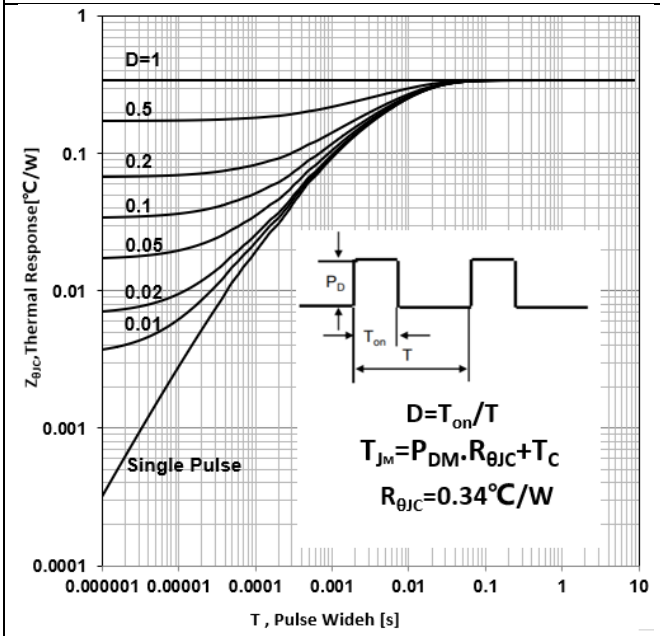


Figure 20. Diode Transient Thermal Impedance vs Pulse Width

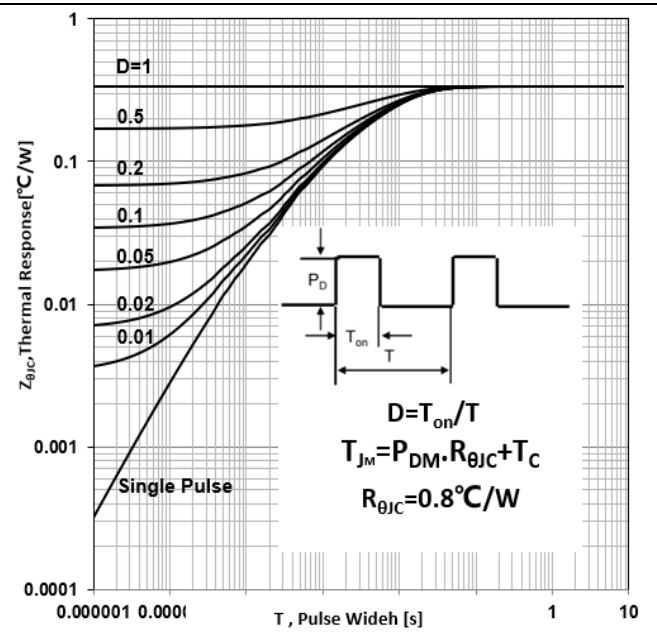
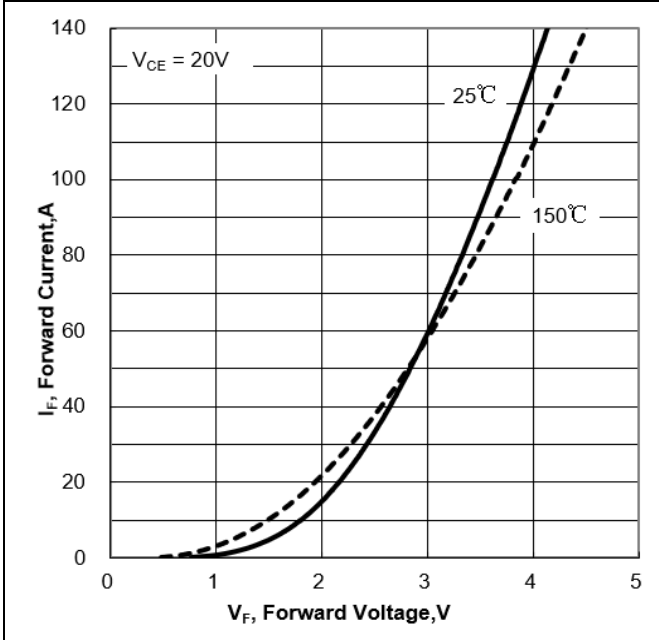
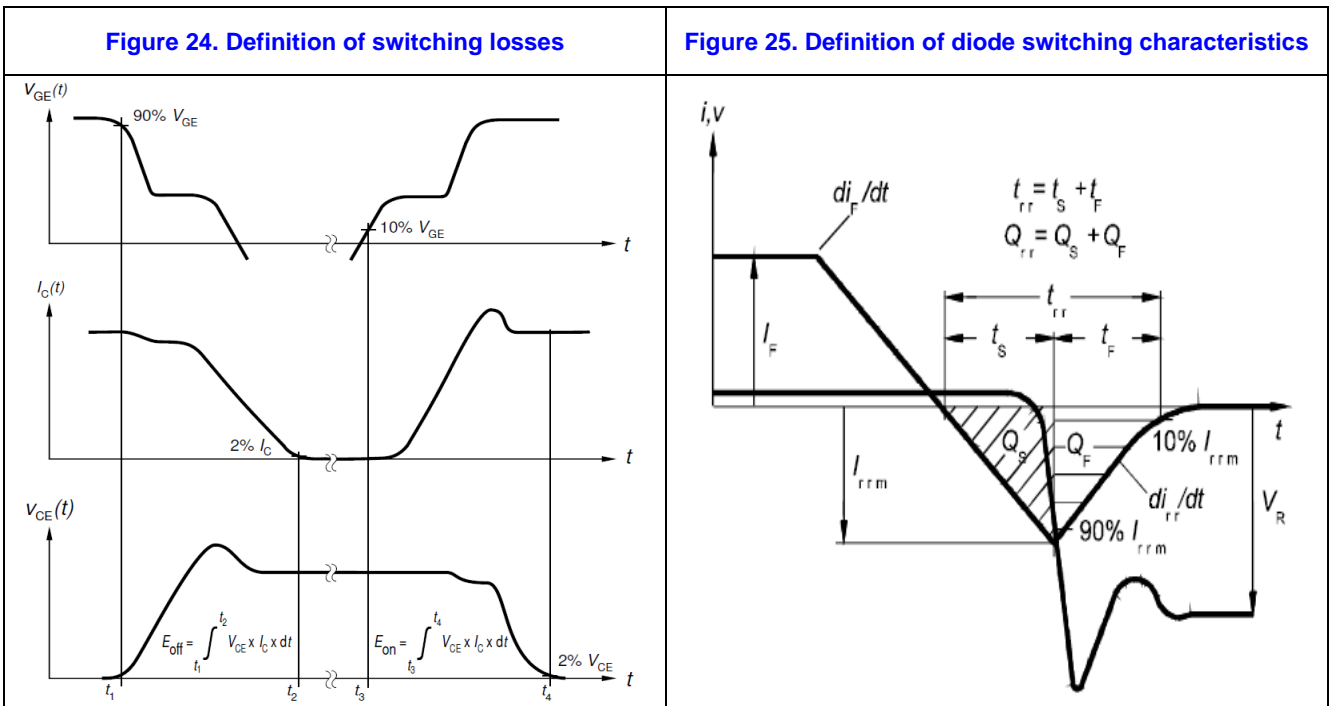
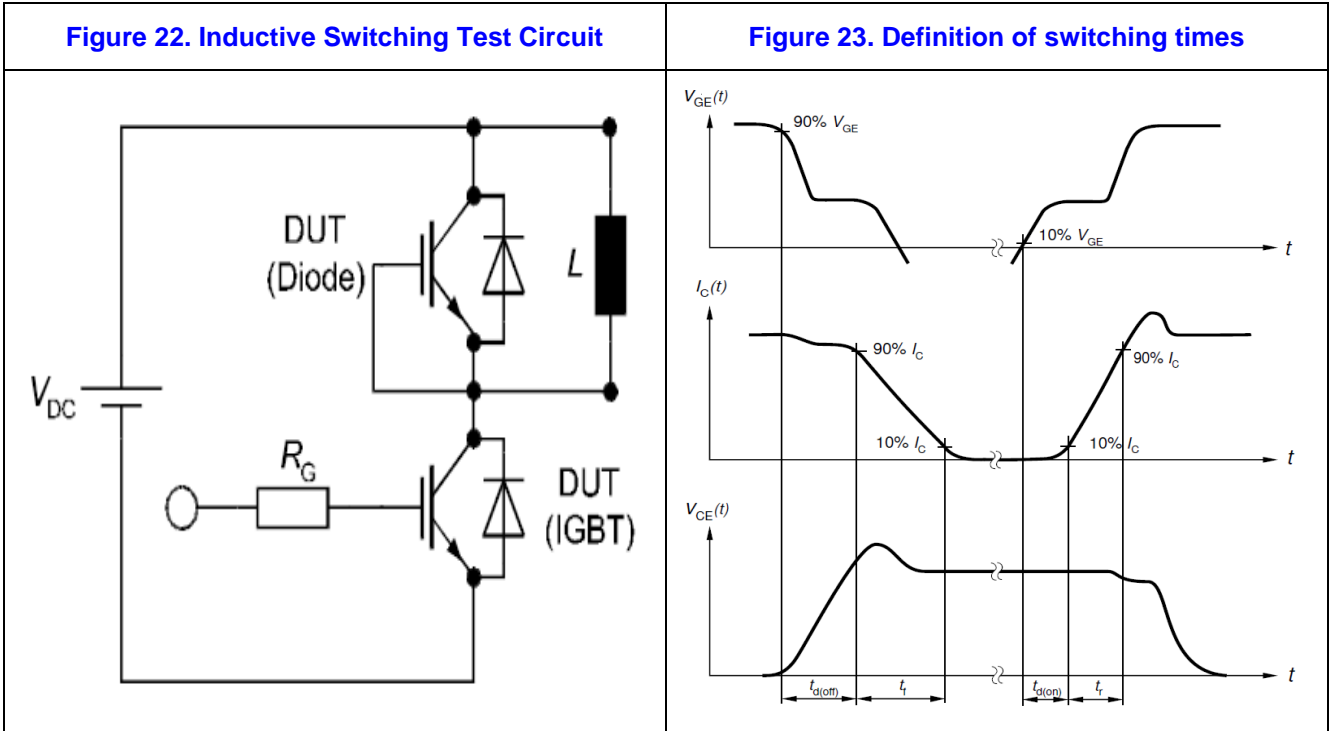




Figure 21. Typical Diode Forward Current vs Forward Voltage

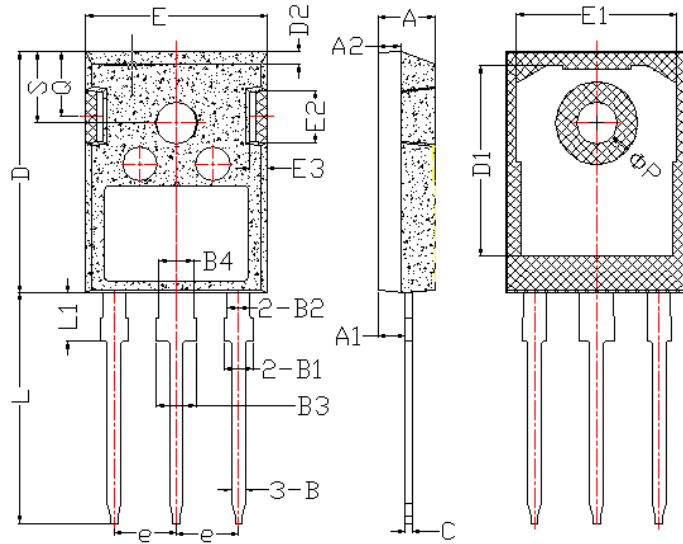


## 6. Test Circuit and Waveform





## 7. Package Description



TO-247 Package

Items	Values(mm)	
	MIN	MAX
A	4.90	5.16
A1	2.27	2.53
A2	1.85	2.11
B	1.07	1.33
B1	1.90	2.41
B2	1.75	2.15
B3	2.87	3.38
B4	2.87	3.13
C	0.55	0.68
D	20.82	21.10
D1	16.25	17.65
D2	1.05	1.35
E	15.70	16.03
E1	13.10	14.15
E2	3.68	5.10
E3	1.68	2.60
e	5.44	
L	19.80	20.31
L1	4.17	4.47
$\Phi P$	3.50	3.70
Q	5.49	6.00
S	6.04	6.30



**NOTE:**

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. IGBTs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shanghai Belling reserves the right to make changes in this specification sheet and is subject to change without prior notice.